

Notice of References Cited	Application/Control No. 10/549,515		Applicant(s)/Patent Under Reexamination NAKAMURA ET AL.	
	Examiner Mark Kopec		Art Unit 1796	Page 1 of 1

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*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-2001/0018116	08-2001	Hayashi et al.	428/209
*	B	US-6,494,931	12-2002	Mukuno et al.	75/255
	C	US-			
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	E	US-			
	F	US-			
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	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
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NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
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